

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: SHISHIDO et al

Serial No.: 10/679,290

Filed: October 7, 2003

For: A Method For Measuring Three Dimensional  
Shape Of A Fine Pattern

Art Unit: 2624

Examiner: A. Liew

Conf. No.: 4011

**AMENDMENT**

Mail Stop: Amendment (Fee)  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

July 19, 2007

Sir:

The following amendments and remarks are respectfully submitted in connection with the above-identified application, in response to the Office Action dated March 20, 2007. The amendments are listed below and set forth on the following pages.

Amendments to the Claims; and

Remarks are included following the amendments.